

Search Notes

Application/Control No.

10/729,123

Examiner

NAMITHA PILLAI

Applicant(s)/Patent under
Reexamination

SCHLUETTER ET AL.

Art Unit

2173

SEARCHED

Class	Subclass	Date	Examiner
715	858	2/2/2006	NP
705	37	2/2/2006	NP
715	856	2/3/2006	NP
715	962	2/3/2006	NP
705	35	2/3/2006	NP
273	278	2/3/2006	NP
705	10	3/15/2007	NP
715	771	3/12/2007	NP
715	858	3/15/2007	NP
705	37	3/15/2007	NP
715	962	3/15/2007	NP
715	825	3/15/2007	NP
715	844	3/15/2007	NP
715	856	3/15/2007	NP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Databases used: USPAT; US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB; Internet; CiteSeer; Examiner's Electronic Digest	2/2/2006	NP
Database used: IEEE Xplore	2/3/2006	NP
See search report for keyword search terms used	2/2/2006	NP
Consulted with Tadesse Hailu	3/16/2007	NP
Updated search: See search report for keyword search terms used	3/12/2007	NP
Updated search: See search report for keyword search terms used	2/12/2008	NP

Search Notes (continued)

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